



ALPHA & OMEGA
SEMICONDUCTOR



AOL1704

N-Channel Enhancement Mode Field Effect Transistor

SRFET™

General Description

SRFET™ AOL1704 uses advanced trench technology with a monolithically integrated Schottky diode to provide excellent $R_{DS(ON)}$, and low gate charge. This device is suitable for use as a low side FET in SMPS, load switching and general purpose applications.

-RoHS Compliant

-Halogen and Antimony Free Green Device*

Features

V_{DS} (V) = 30V

I_D = 50A (V_{GS} = 10V)

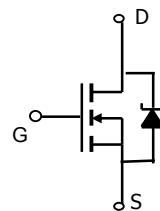
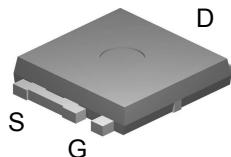
$R_{DS(ON)} < 7.8\text{m}\Omega$ (V_{GS} = 10V)

$R_{DS(ON)} < 9.8\text{m}\Omega$ (V_{GS} = 4.5V)

UIS Tested!

$R_g, C_{iss}, C_{oss}, C_{rss}$ Tested

Ultra SO-8™ Top View



SRFET™
Soft Recovery MOSFET:
Integrated Schottky Diode

Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current ^B	$T_C=25^\circ\text{C}$ ^I	50	A
$T_C=100^\circ\text{C}$	I_D	43	
Pulsed Drain Current	I_{DM}	120	
Continuous Drain Current ^H	$T_A=25^\circ\text{C}$	12	A
$T_A=70^\circ\text{C}$	I_{DSM}	10	
Avalanche Current ^C	I_{AR}	25	A
Repetitive avalanche energy $L=0.3\text{mH}$ ^C	E_{AR}	94	mJ
Power Dissipation ^B	$T_C=25^\circ\text{C}$	50	W
$T_C=100^\circ\text{C}$	P_D	25	
Power Dissipation ^A	$T_A=25^\circ\text{C}$	2.0	W
$T_A=70^\circ\text{C}$	P_{DSM}	1.3	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 175	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$t \leq 10\text{s}$	24	29	°C/W
Maximum Junction-to-Ambient ^A		53	64	°C/W
Maximum Junction-to-Case ^C	$R_{\theta JC}$	2.4	3.0	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}, V_{GS}=0\text{V}$		0.04	0.1	mA
		$T_J=125^\circ\text{C}$		5	20	
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$			0.1	μA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.4	1.8	2.4	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	120			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$		6.5	7.8	$\text{m}\Omega$
		$T_J=125^\circ\text{C}$		9.2	11.5	
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		95		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.36	0.5	V
I_S	Maximum Body-Diode + Schottky Diode Continuous Current [†]				50	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		2800	3640	pF
C_{oss}	Output Capacitance			390		pF
C_{rss}	Reverse Transfer Capacitance			145		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		0.8	1.2	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=20\text{A}$		42	50	
$Q_g(4.5\text{V})$	Total Gate Charge			19	23	nC
Q_{gs}	Gate Source Charge			7		nC
Q_{gd}	Gate Drain Charge			6		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=0.75\Omega, R_{\text{GEN}}=3\Omega$		7		ns
t_r	Turn-On Rise Time			7		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			31		ns
t_f	Turn-Off Fall Time			5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=300\text{A}/\mu\text{s}$		13	16	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=300\text{A}/\mu\text{s}$		12		nC

A: The value of $R_{\theta JA}$ is measured with the device in a still air environment with $T_A=25^\circ\text{C}$. The power dissipation P_{DSM} and current rating I_{DSM} are based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $t \leqslant 10\text{s}$ junction-to-ambient thermal resistance.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=175^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C: Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=175^\circ\text{C}$.

D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 us pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=175^\circ\text{C}$.

G. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

H. Surface mounted on a 1 in 2 FR-4 board with 2oz. Copper.

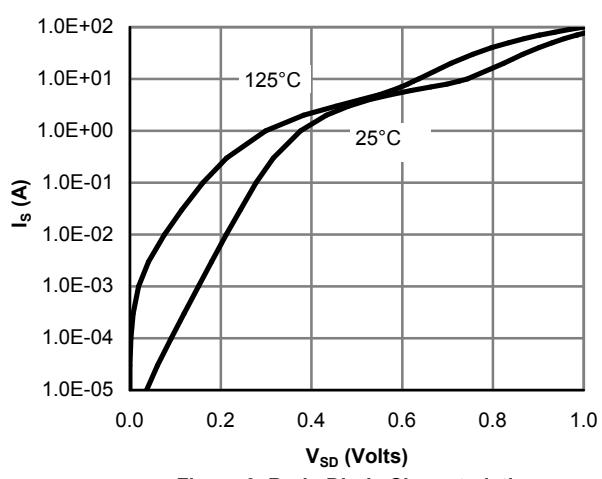
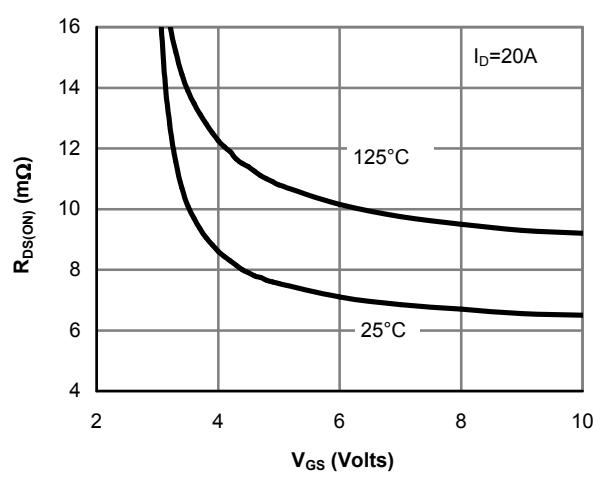
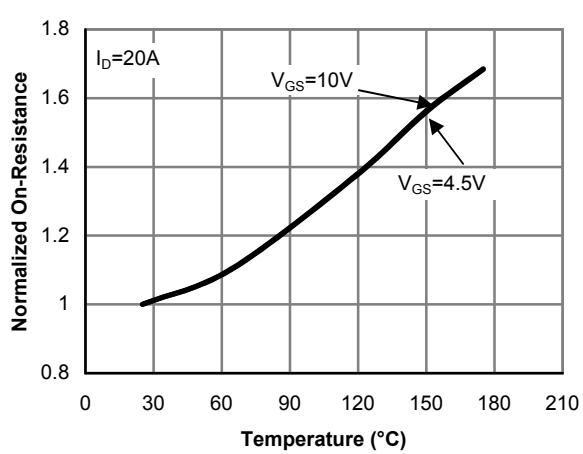
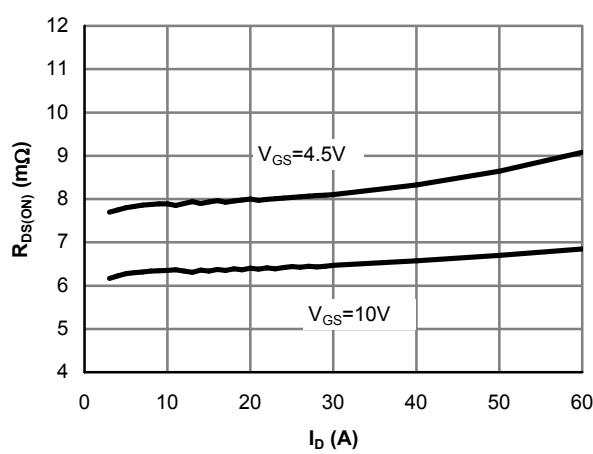
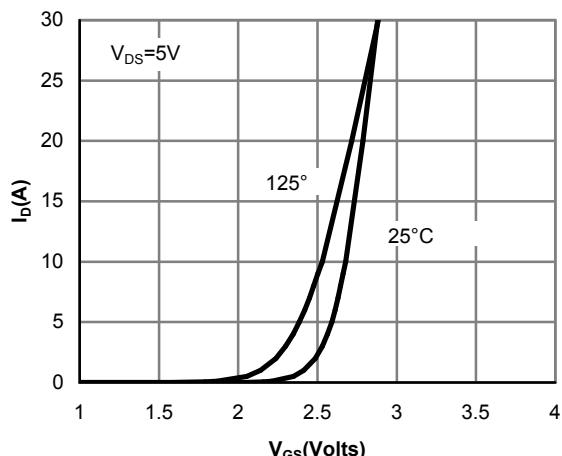
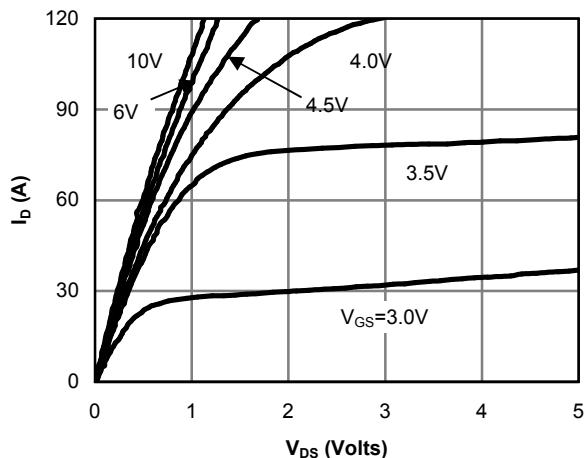
I. The maximum current rating is limited by bond-wires.

* This device is guaranteed green after date code 8P11 (June 1ST 2008)

Rev2: July, 2008

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



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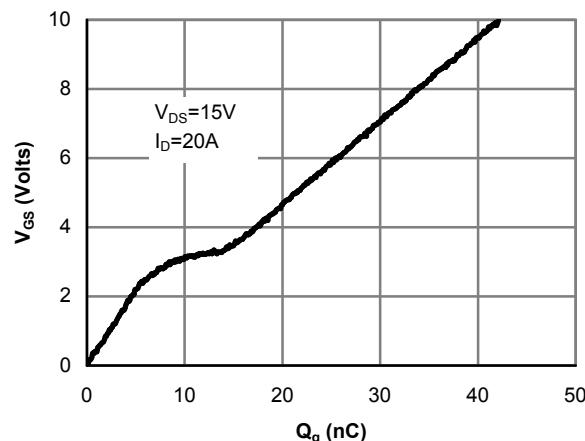


Figure 7: Gate-Charge Characteristics

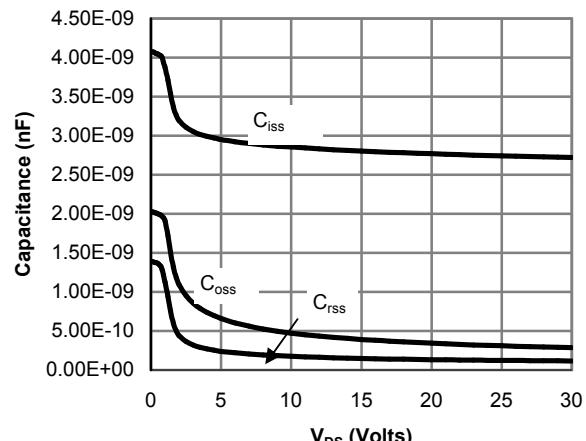


Figure 8: Capacitance Characteristics

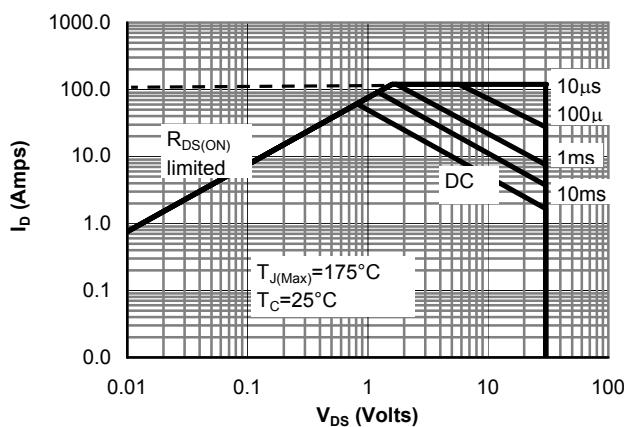


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

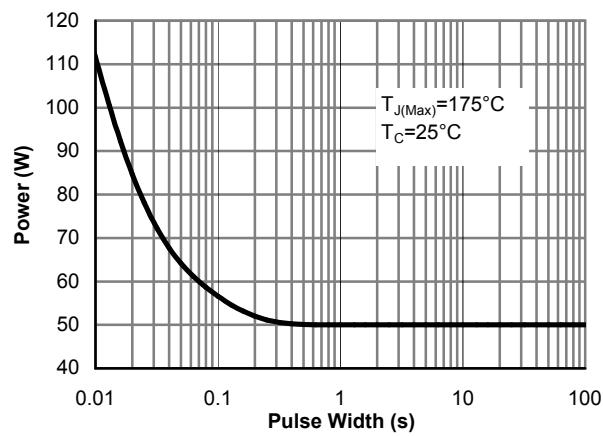


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

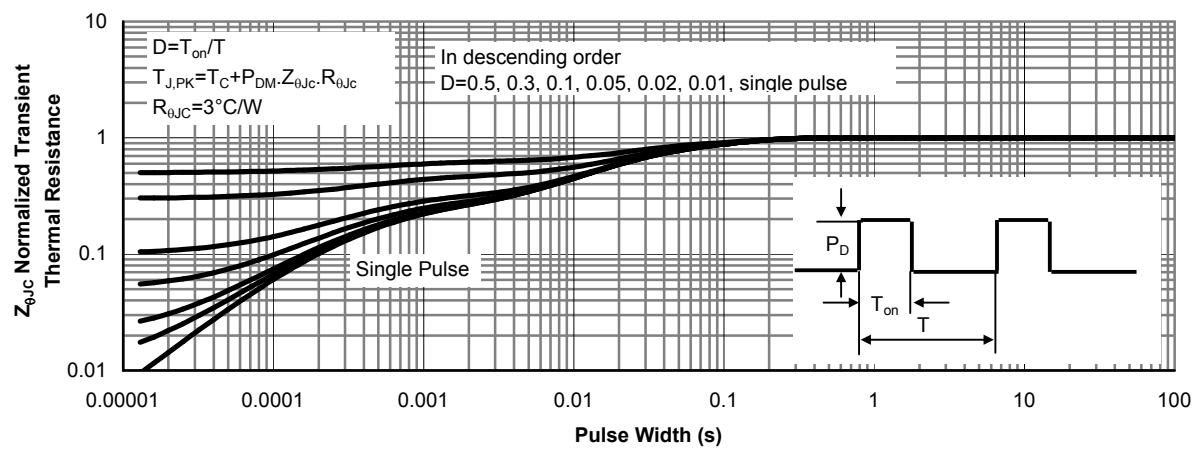


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

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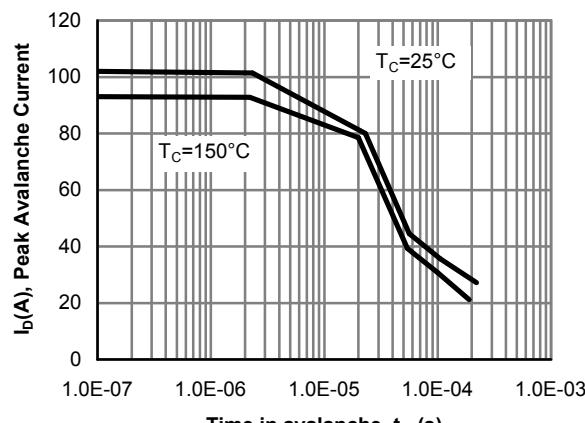


Figure 12: Single Pulse Avalanche capability

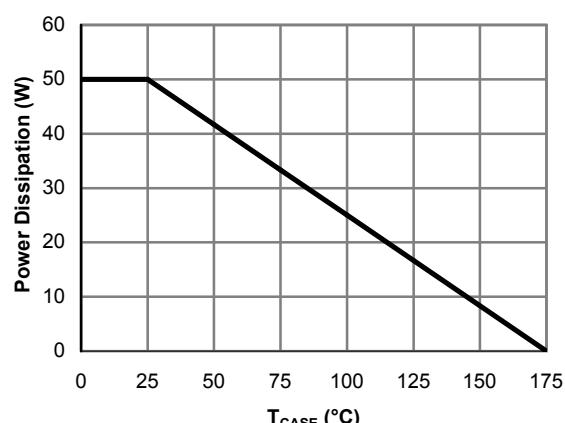


Figure 13: Power De-rating (Note B)

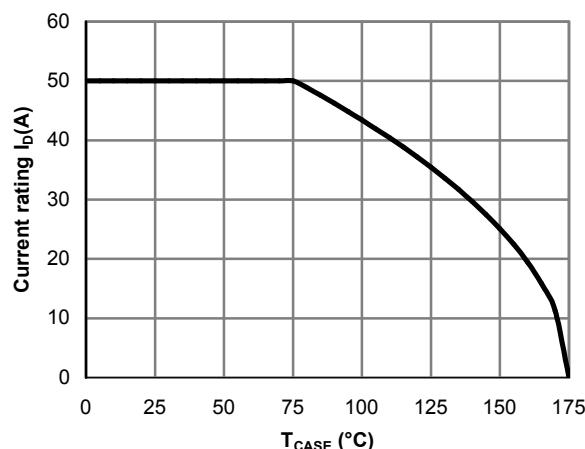


Figure 14: Current De-rating (Note B)

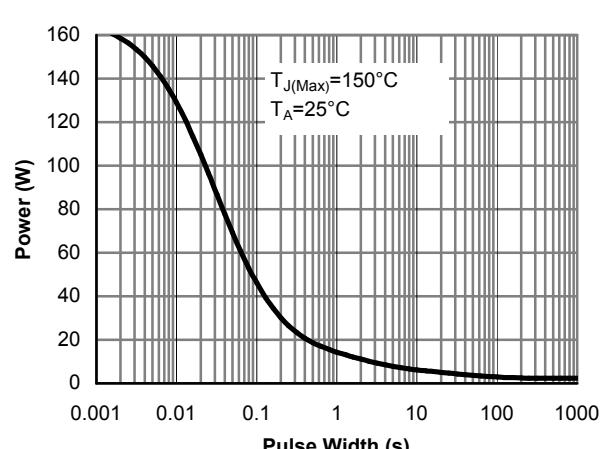


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note G)

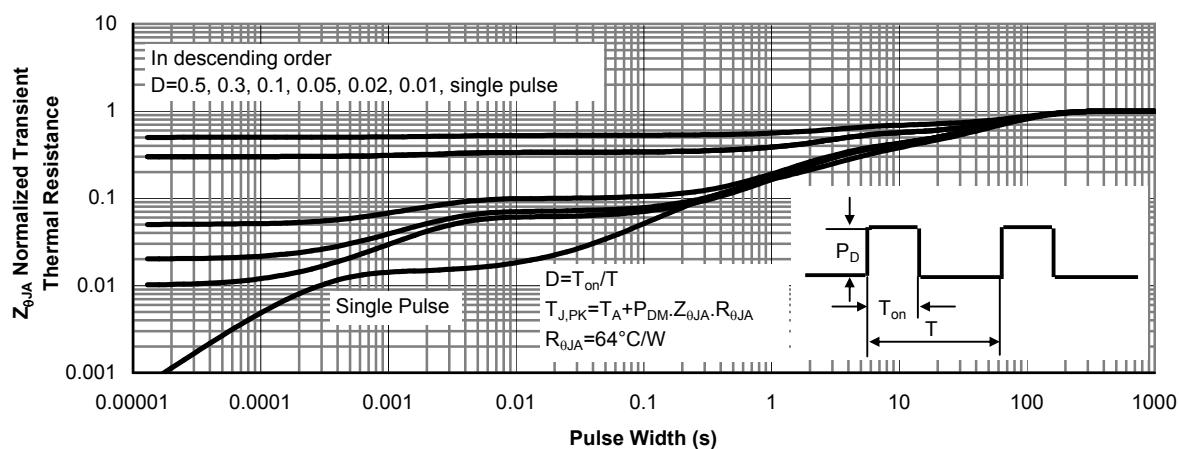
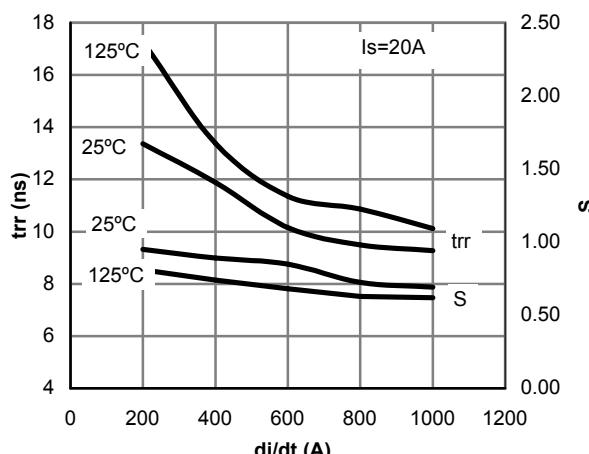
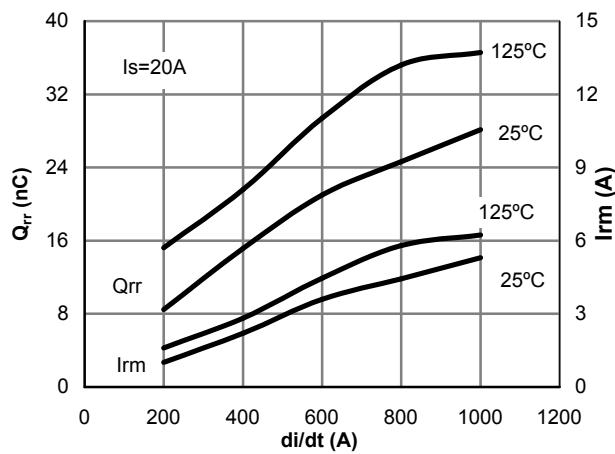
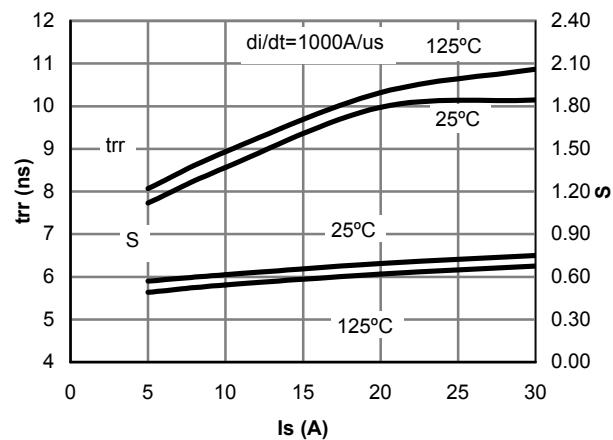
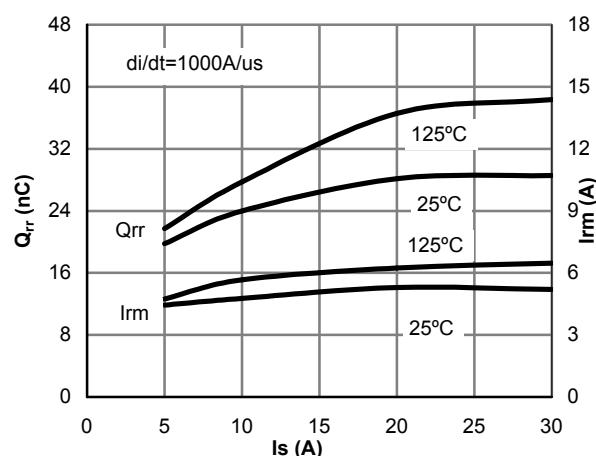
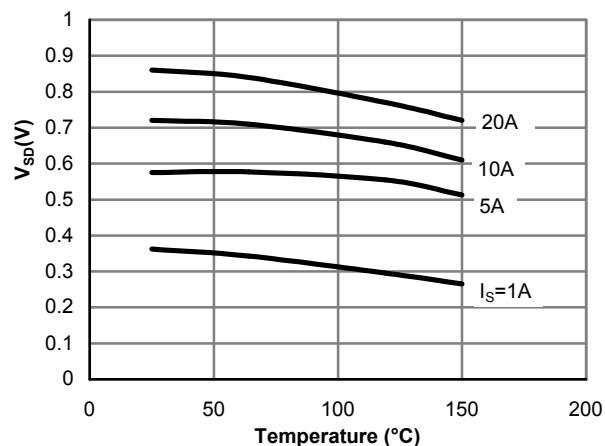
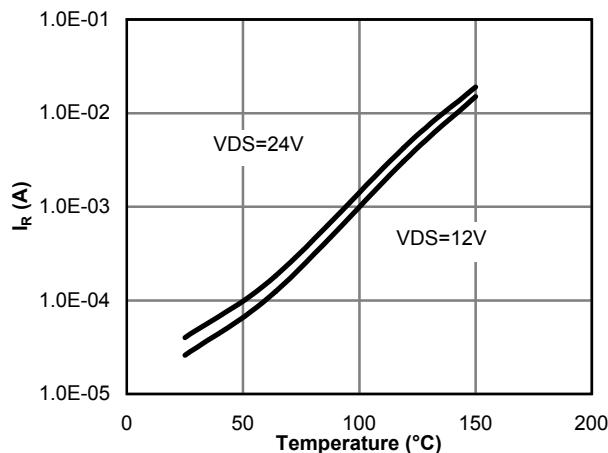
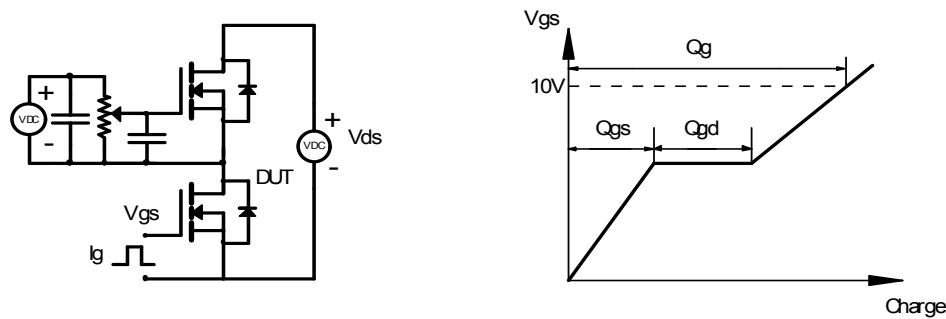


Figure 16: Normalized Maximum Transient Thermal Impedance (Note G)

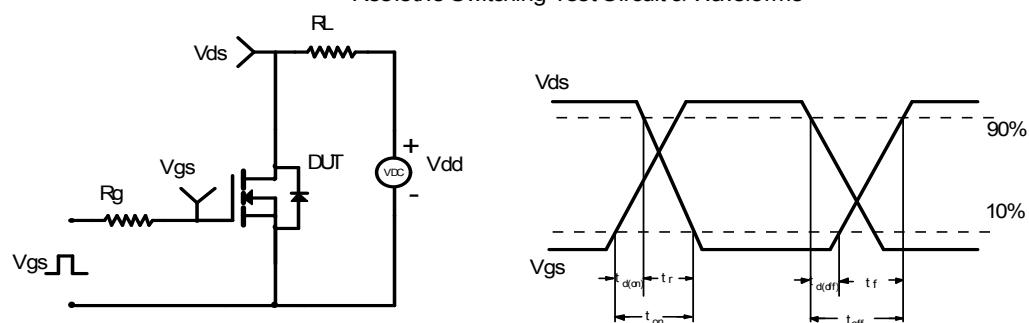
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



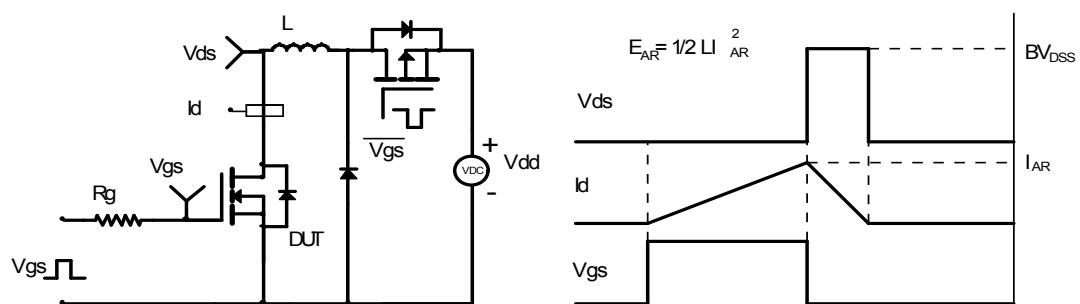
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

